Search Notes Application/Control No. Applicant(s)/Patent Under Reexamination WALKER ET AL. Examiner Lee, Siu M Applicant(s)/Patent Under Reexamination WALKER ET AL.

SEARCHED					
Class	Subclass	Date	Examiner		
370	323, 334	10/31/2006	Siu M. Lee		
710	38	10/31/2006	Siu M. lee		
455	3.01,3.02,3.03,3.04,7,427,428,12.1,181.1,171.1,178.1,18 6,191.1,456.1,457,414.1,161.2,161.3,166.2,184.1,419,34 5	10/31/2006	Siu M. Lee		
710	38	4/27/2007	Siu M. Lee		
375	132-137	4/27/2007	Siu M. Lee		
455	3.01,7,427,3.02,3.03,428,12.1,3.04,3.06,556,181.1,171.1 ,178.1,186.1,191.1,193.1,193.2,132,184,187,456.1,457,4 14.1,419,345,456.3,20,74,18,66,45,6.3,4.1,4.2,103	4/27/2007	Siu M. Lee		
370	316,330,478,132,328,329,335-338,340-342	4/27/2007	Siu M. Lee		

SEARCH NOTES					
Search Notes	Date	Examiner			
EAST	10/25/2006	Siu M. Lee			
consult primary examiner of 370 (John Pezzlo)	10/27/2006	Siu M. Lee			
Discuss the application with SPE (Chieh Fan)	10/30/2006	Siu M. Lee			
EAST	4/27/2007	Siu M. Lee			
Discuss application and amendment with Chieh Fan	4/27/2007	Siu M. Lee			
EAST	10/17/2007	Siu M. Lee			
Discuss the RCE with Chieh Fan	10/17/2007	Siu M. Lee			
EAST	4/17/2008	Siu M. Lee			
Discuss the application with Chieh Fan	4/17/2008	Siu M. Lee			

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		

U.S. Patent and Trademark Office Part of Paper No.: